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TEST REPORT

Report No.: CQASZ20250801837E-03

Applicant: Deep Intelligence Technology (Wenzhou) Co., Ltd.

Address of Applicant: Room 201, 2nd Floor, Building A7, Phase II, Wenzhou Fintech & Cultural Center,

Qidu Subdistrict, Lucheng District, Wenzhou, Zhejiang Province, China

Equipment Under Test (EUT):

EUT Name: SMART EYEWEAR

Model No.: SZ-2503

Test Model No.: SZ-2503

Brand Name: N/A

FCC ID: 2BRGE-SZ-2503

47 CFR Part 1.1307

Standards: 47 CFR Part 1.1310

KDB447498D01 General RF Exposure Guidance v06

Date of Receipt: 2025-08-07

Date of Test: 2025-08-07 to 2025-08-18

Date of Issue: 2025-9-2
Test Result: PASS

Tested By:

(Lewis Zhou)

Reviewed By:

(Timo Lei)

Approved By:

(Jack Ai)



The test report is effective only with both signature and specialized stamp, The result(s) shown in this report refer only to the sample(s) tested. Without written approval of CQA, this report can't be reproduced except in full.



1. Version

Revision History Of Report

Report No.	Version	Description	Issue Date
CQASZ20250801837E-03	Rev.01	Initial report	2025-9-2





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3. General Information

4. Client Information

Applicant:	Deep Intelligence Technology (Wenzhou) Co., Ltd.
Address of Applicant:	Room 201, 2nd Floor, Building A7, Phase II, Wenzhou Fintech & Cultural Center, Qidu Subdistrict, Lucheng District, Wenzhou, Zhejiang Province, China
Manufacturer:	Deep Intelligence Technology (Wenzhou) Co., Ltd.
Address of Manufacturer:	Room 201, 2nd Floor, Building A7, Phase II, Wenzhou Fintech & Cultural Center, Qidu Subdistrict, Lucheng District, Wenzhou, Zhejiang Province, China
Factory:	Deep Intelligence Technology (Wenzhou) Co., Ltd.
Address of Factory:	Room 201, 2nd Floor, Building A7, Phase II, Wenzhou Fintech & Cultural Center, Qidu Subdistrict, Lucheng District, Wenzhou, Zhejiang Province, China

5. General Description of EUT

or contra becompation of Lot			
Product Name:	SMART EYEWEAR		
Model No.:	SZ-2503		
Test Model No.:	SZ-2503		
Trade Mark:	N/A		
Software Version:	V1.0.0		
Hardware Version:	V1.0.0		
Modulation Technique:	Frequency Hopping Spread Spectrum(FHSS)		
Modulation Type:	GFSK		
Transfer Rate:	1Mbps/2Mbps		
Number of Channel:	40		
Antenna Type:	SMD antenna		
Antenna Gain:	0.2dBi		
Product Type:	☐ Mobile ☐ Portable ☐ Fix Location		
Power Supply:	2*Li-ion battery: DC 3.7V 100mAh, Charge by DC 5V for adapter		





RF Exposure Evaluation

RF Exposure Compliance Requirement

Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where f(GHz) is the RF channel transmit frequency in GHz Power and distance are rounded to the nearest mW and mm before calculation17

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is \leq 5 mm, a distance of 5 mm is applied to determine SAR test exclusion





EUT RF Exposure

1) For BT (Left)

Measurement Data

Worst case: 8DPSK				
Test Channel	Peak Output Power	Tune up tolerance	Maximum tune-up Power	
l est Ollallilei	(dBm)	(dBm)	(dBm)	(mW)
Lowest(2402MHz)	1.43	1.5±1	2.5	1.78
Middle(2441MHz)	1.71	2.0±1	3	2.00
Highest(2480MHz)	1.37	1.5±1	2.5	1.78

Maximum tuneup Power (mW)	Calculated value	Exclusion threshold
1.78	0.551	
2.00	0.623	3.0
1.78	0.560	
	1.78 2.00	(mW) 0.551 1.78 0.623 2.00 0.560

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20250801837E-01



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2) For BT (Right)

Measurement Data

Worst case: 8DPSK				
Test Channel	Peak Output Power	Tune up tolerance	Maximum tune-up Power	
rest Chamber	(dBm)	(dBm)	(dBm)	(mW)
Lowest(2402MHz)	1.93	2.0±1	3	1.995
Middle(2441MHz)	1.66	2.0±1	3	1.995
Highest(2480MHz)	1.22	1.5±1	2.5	1.778

Worst case: 8DPSK	(1	1
Channel	Maximum tuneup Power (mW)	Calculated value	Exclusion threshold
Lowest (2402MHz)	1.995	0.618	
Middle (2441MHz)	1.995	0.623	3.0
Highest (2480MHz)	1.778	0.560	
Conclusion: the calculated value ≤3.0, SAR is exempted.			

Remark: The Max Conducted Peak Output Power data refer to report Report No.: CQASZ20250801837E-02

Simultaneous transmission:

SAR Exclusion Threshold=

[(max. power of channel, including tune-up tolerance, mW)/

(min. test separation distance, mm)] ·[√f(GHz)]

BLE (Left)+BLE (Right):

=[$(2mW/5mm) \cdot \sqrt{2.48GHz}$]/1.6W/kg+[$(1.995mW/5mm) \cdot \sqrt{2.441GHz}$]/1.6W/kg

=0.39+0.39

=0.78≤1

*** END OF REPORT ***